

Data Sheet

January 2002

18A, 200V, 0.180 Ohm, N-Channel Power MOSFETs

These are N-Channel enhancement mode silicon gate power field effect transistors. They are advanced power MOSFETs designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching convertors, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. These types can be operated directly from integrated circuits.

Formerly developmental type TA17422.

Ordering Information

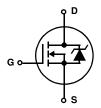
PART NUMBER	PACKAGE	BRAND
IRF640	TO-220AB	IRF640
RF1S640	TO-262AA	RF1S640
RF1S640SM	TO-263AB	RF1S640

NOTE: When ordering, use the entire part number. Add the suffix 9A to obtain the TO-263AB variant in the tape and reel, i.e., RF1S640SM9A.

Features

- 18A, 200V
- $r_{DS(ON)} = 0.180\Omega$
- · Single Pulse Avalanche Energy Rated
- · SOA is Power Dissipation Limited
- · Nanosecond Switching Speed
- · Linear Transfer Characteristics
- · High Input Impedance
- · Related Literature
 - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

Symbol



Packaging

JEDEC TO-220AB

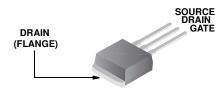
SOURCE DRAIN GATE

DRAIN (FLANGE)

JEDEC TO-263AB



JEDEC TO-262AA



IRF640, RF1S640, RF1S640SM

Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

	IRF640, RF1S640, RF1S640SM	UNITS
Drain to Source Breakdown Voltage (Note 1)	200	V
Drain to Gate Voltage ($R_{GS} = 20k\Omega$) (Note 1)	200	V
Continuous Drain Current	18	Α
$T_C = 100^{\circ}C$ I_D	11	Α
Pulsed Drain Current (Note 3)	72	Α
Gate to Source Voltage	±20	V
Maximum Power Dissipation	125	W
Dissipation Derating Factor	1.0	W/oC
Single Pulse Avalanche Energy Rating (Note 4)EAS	580	mJ
Operating and Storage Temperature	-55 to 150	°C
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10s	300	°C
Package Body for 10s, See TB334	260	°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}C$ to $125^{\circ}C$.

Electrical Specifications $T_C = 25^{\circ}C$, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	BV _{DSS}	$I_D = 250\mu A, V_{GS} = 0V, (Figure 10)$		200	-	-	V
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D = 250μA		2	-	4	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = Rated BV _{DSS} , V _{GS} = 0V		-	-	25	μΑ
		V _{DS} = 0.8 x Rated BV _{DSS} ,	$V_{GS} = 0V, T_J = 125^{\circ}C$	-	-	250	μΑ
On-State Drain Current (Note 1)	I _{D(ON)}	$V_{DS} > I_{D(ON)} \times r_{DS(ON)MA}$	x, V _{GS} = 10V (Figure 7)	18	-	-	Α
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V$		-	-	±100	nA
Drain to Source On Resistance (Note 1)	r _{DS(ON)}	$I_D = 10A$, $V_{GS} = 10V$ (Figur	res 8, 9)	-	0.14	0.18	Ω
Forward Transconductance (Note 1)	9fs	$V_{DS} \ge 10V$, $I_D = 11A$ (Figur	re 12)	6.7	10	-	S
Turn-On Delay Time	t _{d(ON)}	$V_{DD} = 100V, I_D \approx 18A, R_{GS} = 9.1\Omega, R_L = 5.4\Omega, \\ MOSFET Switching Times are Essentially \\ Independent of Operating Temperature$		-	13	21	ns
Rise Time	t _r			-	50	77	ns
Turn-Off Delay Time	t _d (OFF)			-	46	68	ns
Fall Time	t _f			-	35	54	ns
Total Gate Charge (Gate to Source + Gate to Drain)	$Q_{g(TOT)}$	V_{GS} = 10V, I_{D} \approx 18A, V_{DS} = 0.8 x Rated BV _{DSS} (Figure 14) Gate Charge is Essentially Independent of Operating Temperature $I_{G(REF)}$ = 1.5mA		-	43	64	nC
Gate to Source Charge	Q _{gs}			-	8	-	nC
Gate to Drain "Miller" Charge	Q _{gd}			-	22	-	nC
Input Capacitance	C _{ISS}	V _{DS} = 25V, V _{GS} = 0V, f = 1MHz (Figure 11)		-	1275	-	pF
Output Capacitance	C _{OSS}			-	400	-	pF
Reverse Transfer Capacitance	C _{RSS}			-	100	-	pF
Internal Drain Inductance	L _D	Measured From the Contact Screw on Tab to Center of Die Modified MOSFET Symbol Showing the Internal Devices	-	3.5	-	nH	
		Measured From the Drain Lead, 6mm (0.25in) From Package to Center of Die	ad, 6mm (0.25in) From	-	4.5	-	nH
Internal Source Inductance	L _S	Measured From the Source Lead, 6mm (0.25in) from Header to Source Bonding Pad	G CLS	-	7.5	-	nH
Thermal Resistance Junction to Case	$R_{ heta JC}$			-	-	1	°C/W
Thermal Resistance Junction to	$R_{\theta JA}$	Free Air Operation, IRF640 RF1S640SM Mounted on FR-4 Board with Minimum Mounting Pad		-	-	62	°C/W
Ambient	$R_{\theta JA}$			-	-	62	°C/W

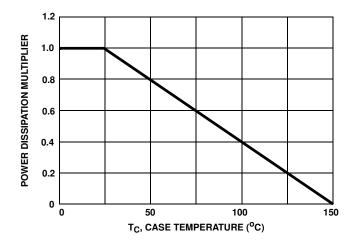
Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Continuous Source to Drain Current	I _{SD}	Modified MOSFET	o D	-	-	18	Α
Pulse Source to Drain Current (Note 2)	^I SDM	Symbol Showing the Integral Reverse P-N Junction Diode	Go	-	-	72	A
Source to Drain Diode Voltage (Note 2)	V_{SD}	$T_J = 25^{\circ}C$, $I_{SD} = 18A$, $V_{GS} = 0V$, (Figure 13)		-	-	2.0	V
Reverse Recovery Time	t _{rr}	$T_J = 25^{\circ}C$, $I_{SD} = 18A$, $dI_{SD}/dt = 100A/\mu s$		120	240	530	ns
Reverse Recovery Charge	Q _{RR}	$T_J = 25^{\circ}C$, $I_{SD} = 18A$, $dI_{SD}/dt = 100A/\mu s$		1.3	2.8	5.6	μC

NOTES:

- 2. Pulse Test: Pulse width $\leq 300 \mu s$, duty cycle $\leq 2\%$.
- 3. Repetitive Rating: Pulse width limited by maximum junction temperature. See Transient Thermal Impedance curve (Figure 3).
- 4. V_{DD} = 50V, starting T_J = 25°C, L = 3.37mH, R_G = 25 Ω , peak I_{AS} = 18A.

Typical Performance Curves Unless Otherwise Specified



20 (e) 16 12 12 13 14 0 25 50 75 100 125 150 T_C, CASE TEMPERATURE (°C)

FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

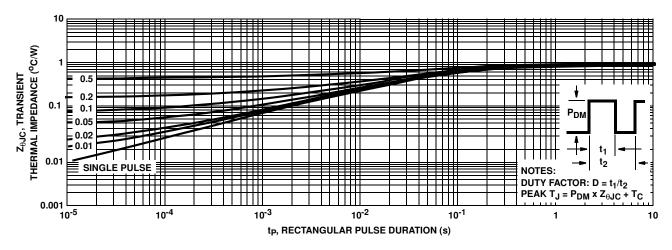


FIGURE 3. MAXIMUM TRANSIENT THERMAL IMPEDANCE

Typical Performance Curves Unless Otherwise Specified (Continued)

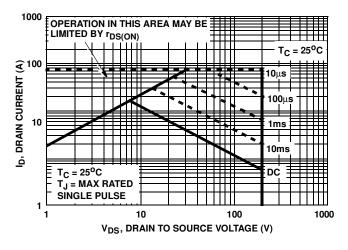


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

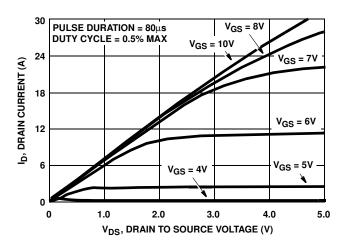


FIGURE 6. SATURATION CHARACTERISTICS

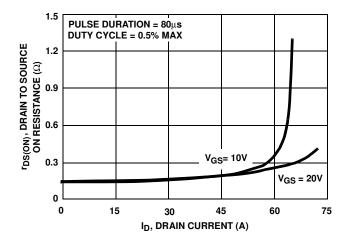


FIGURE 8. DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE AND DRAIN CURRENT

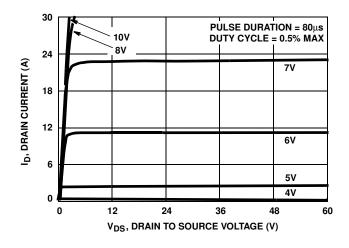


FIGURE 5. OUTPUT CHARACTERISTICS

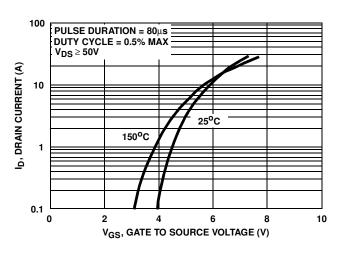


FIGURE 7. TRANSFER CHARACTERISTICS

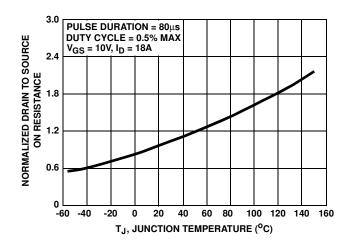


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

Typical Performance Curves Unless Otherwise Specified (Continued)

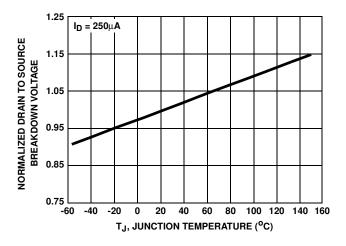


FIGURE 10. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

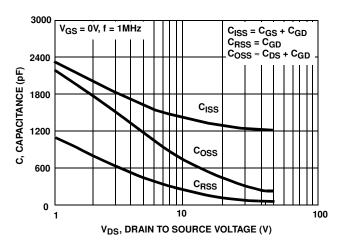


FIGURE 11. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

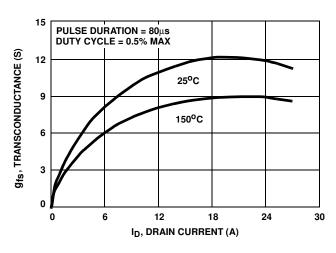


FIGURE 12. TRANSCONDUCTANCE vs DRAIN CURRENT

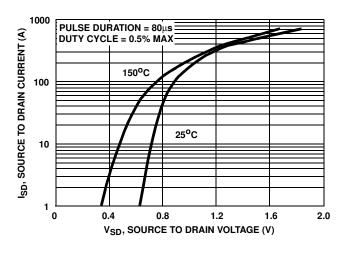


FIGURE 13. SOURCE TO DRAIN DIODE VOLTAGE

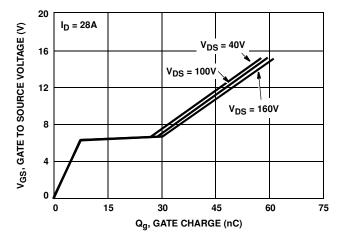


FIGURE 14. GATE TO SOURCE VOLTAGE vs GATE CHARGE

Test Circuits and Waveforms

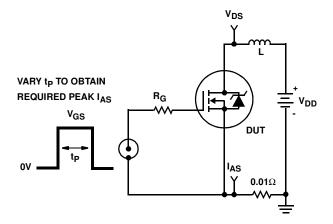


FIGURE 15. UNCLAMPED ENERGY TEST CIRCUIT

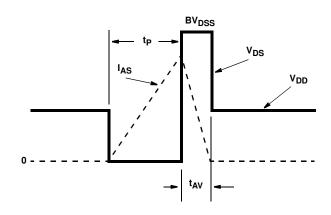


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

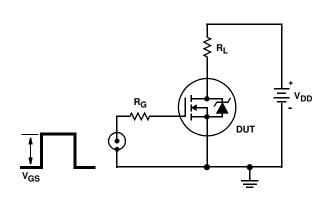


FIGURE 17. SWITCHING TIME TEST CIRCUIT

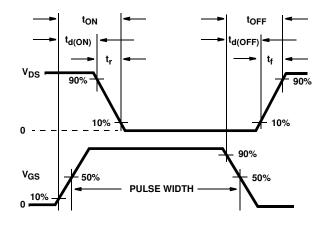


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS

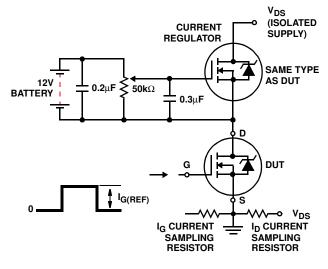


FIGURE 19. GATE CHARGE TEST CIRCUIT

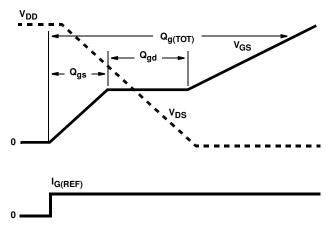


FIGURE 20. GATE CHARGE WAVEFORMS

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